

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 236518US41YA		SERIAL NO. 10/673,138	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Eric J STRANG, et al.			
				FILING DATE September 30, 2003		GROUP 2128	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA	US 2002/0032495 A1	3/14/2002	Ozaki			
	AB	US 5,719,796	2/17/1998	CHEN			
	AC						
	AD						
	AE						
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	AF						
	AG						
	AH						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
	AI	CN 1335558A	2/13/2002	China (with Partial English Translation))	X		
	AJ	JP 11-176906	7/2/1999	JAPAN (with English Abstract)		X	
	AK	KR 1999-071784	4/2/1999	Korea (with corresponding to US. Patent Application No. 5,719,796 attached as a courtesy herewith)	X		
	AL						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AL	Agam SHAH, "TILERA TARGETS INTEL, AMD WITH 100-CORE PROCESSOR", PCWorld Solved, IDG News October 26, 2009, pages 1-3					
	AM	Robert W. ATHERTON, et al., "DETAILED SIMULATION FOR SEMICONDUCTOR MANUFACTURING", Proceedings of the 1990 Winter Simulation Conference, ppgs 659-663					
	AN	Angus J. MACDONALD, et al. "INTEGRATING CAM AND PROCESS SIMULATION TO ENHANCE ON-LINE ANALYSIS AND CONTROL OF IC FABRICATION", IEEE Transactions On Semiconductor Conductor Manufacturing, Vol., 3. No. 2, May 1990, pages 72-79					
	AO	Yea-Huey Su, et al, "A CONCEPTUAL FRAMEWORK FOR MANUFACTURING SERVICE PROVISIONING BY VIRTUAL FABS", 1998 Semiconductor Manufacturing Technology Workshop, pages 75-85					
	AP	Chanette RASMIDATTA, et al. "NEW APPROACHES FOR SIMULATION OF WAFER FABRICATION: THE USE OF CONTROL VARIATES AND CALIBRATION METRICS", Proceedings of the 2002 Winter Simulation Conference, pages 1414-1422					
	AQ	Office Action issued March 30, 2011 in Japanese Patent Application No. 10-2006-7006632, (with English-language Translation) pages 1-17					
	AR	Naomi YONEMURA, et al. "HEAT ANALYSIS ON INSULATED METAL SUBSTRATES", Proc. Of the 1994 IMC, 110 (1994), pages 1407-1410					
	AS	Tony C. MIDEA, "1999 CASTING SIMULATION SOFTWARE SURVEY", AFS Process Design and Modeling Committee (1-F), David Schmidt, Finite Solutions, Inc., Arlington Heights, ILL pages 1-4					
	AT					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner					Date Considered		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							